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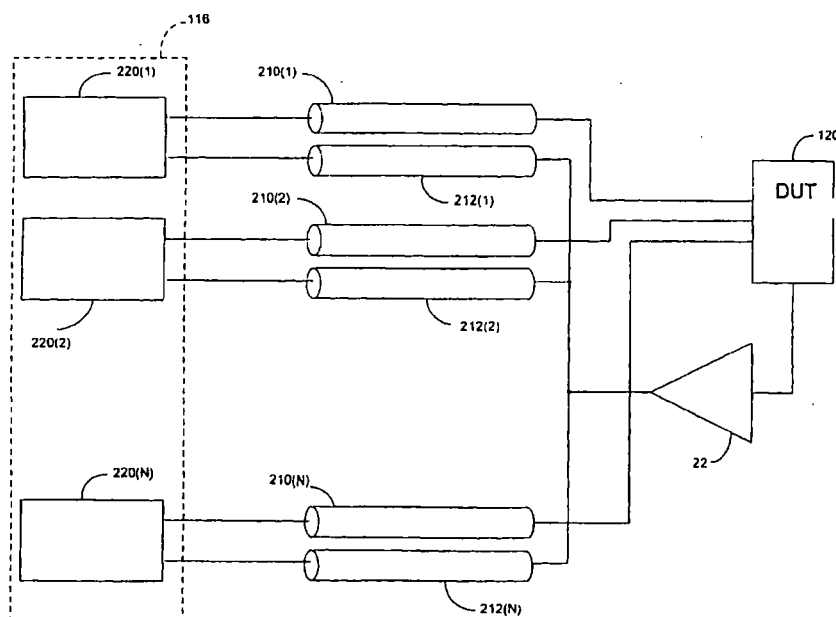
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(54) Title: METHOD AND APPARATUS FOR TESTING SOURCE SYNCHRONOUS INTEGRATED CIRCUITS



(57) Abstract: An automatic test system useful for testing source synchronous devices at high speed. The data outputs of the device under test are routed to channel circuitry within the test system through coaxial cables. The test system includes a buffer amplifier on a device interface board to fan out the DATA CLOCK generated by the device under test to that channel circuitry. The interconnection between the buffer amplifier and the channel circuitry is provided through a coax with low dielectric constant, to compensate for the delay introduced by the buffer amplifier.

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